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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l051c8t6

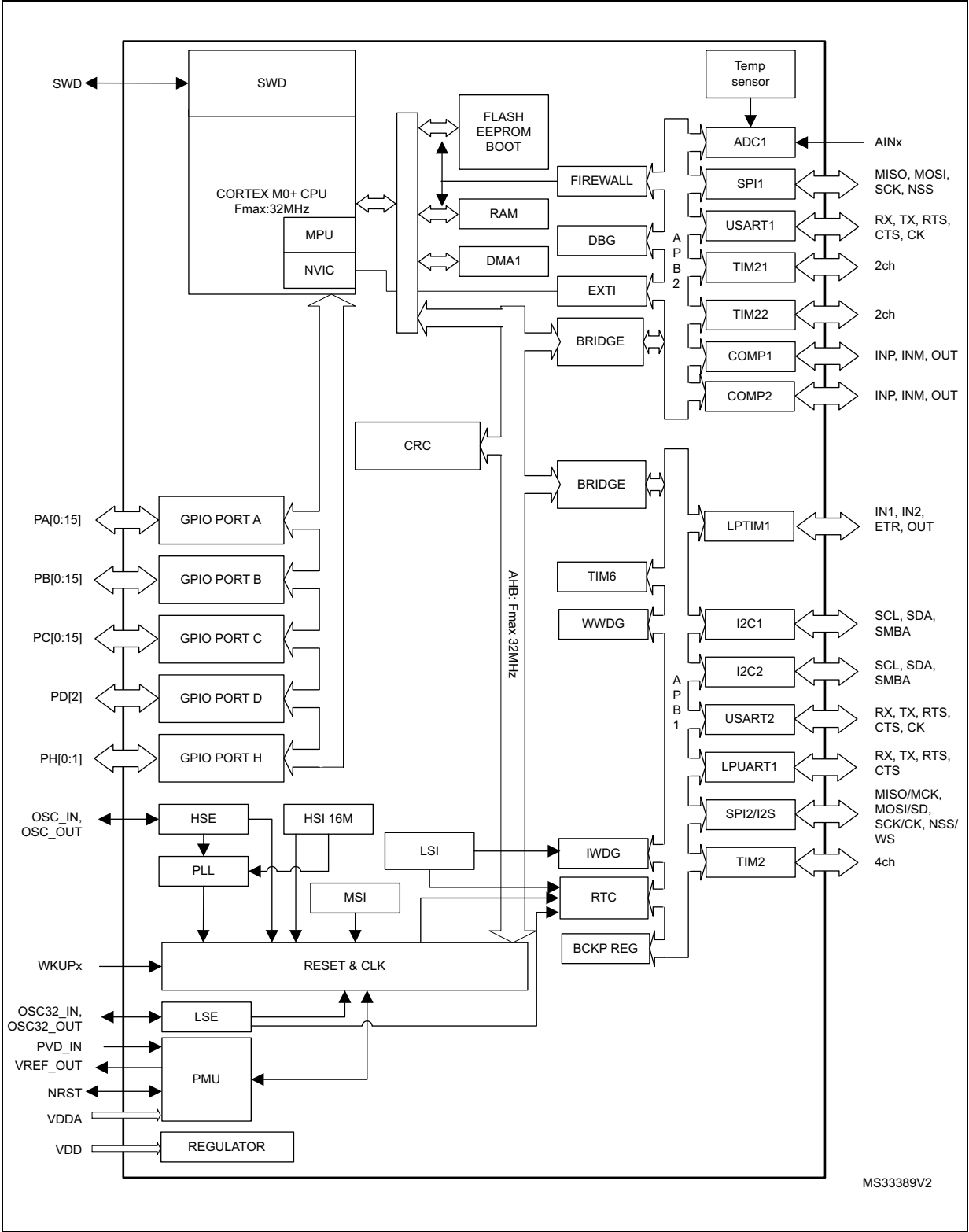
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Figure 1. STM32L051x6/8 block diagram



MS33389V2

**Table 5. Functionalities depending on the working mode
(from Run/active down to standby) (continued)⁽¹⁾**

IPs	Run/Active	Sleep	Low-power run	Low-power sleep	Stop	Standby
					Wakeup capability	Wakeup capability
Consumption $V_{DD}=1.8$ to 3.6 V (Typ)	Down to $140 \mu\text{A}/\text{MHz}$ (from Flash memory)	Down to $37 \mu\text{A}/\text{MHz}$ (from Flash memory)	Down to $8 \mu\text{A}$	Down to $4.5 \mu\text{A}$	$0.4 \mu\text{A}$ (No RTC) $V_{DD}=1.8$ V	$0.28 \mu\text{A}$ (No RTC) $V_{DD}=1.8$ V
					$0.8 \mu\text{A}$ (with RTC) $V_{DD}=1.8$ V	$0.65 \mu\text{A}$ (with RTC) $V_{DD}=1.8$ V
					$0.4 \mu\text{A}$ (No RTC) $V_{DD}=3.0$ V	$0.29 \mu\text{A}$ (No RTC) $V_{DD}=3.0$ V
					$1 \mu\text{A}$ (with RTC) $V_{DD}=3.0$ V	$0.85 \mu\text{A}$ (with RTC) $V_{DD}=3.0$ V

- Legend:
 "Y" = Yes (enable).
 "O" = Optional can be enabled/disabled by software
 "-" = Not available
- Some peripherals with wakeup from Stop capability can request HSI to be enabled. In this case, HSI is woken up by the peripheral, and only feeds the peripheral which requested it. HSI is automatically put off when the peripheral does not need it anymore.
- UART and LPUART reception is functional in Stop mode. It generates a wakeup interrupt on Start. To generate a wakeup on address match or received frame event, the LPUART can run on LSE clock while the UART has to wake up or keep running the HSI clock.
- I2C address detection is functional in Stop mode. It generates a wakeup interrupt in case of address match. It will wake up the HSI during reception.

3.2 Interconnect matrix

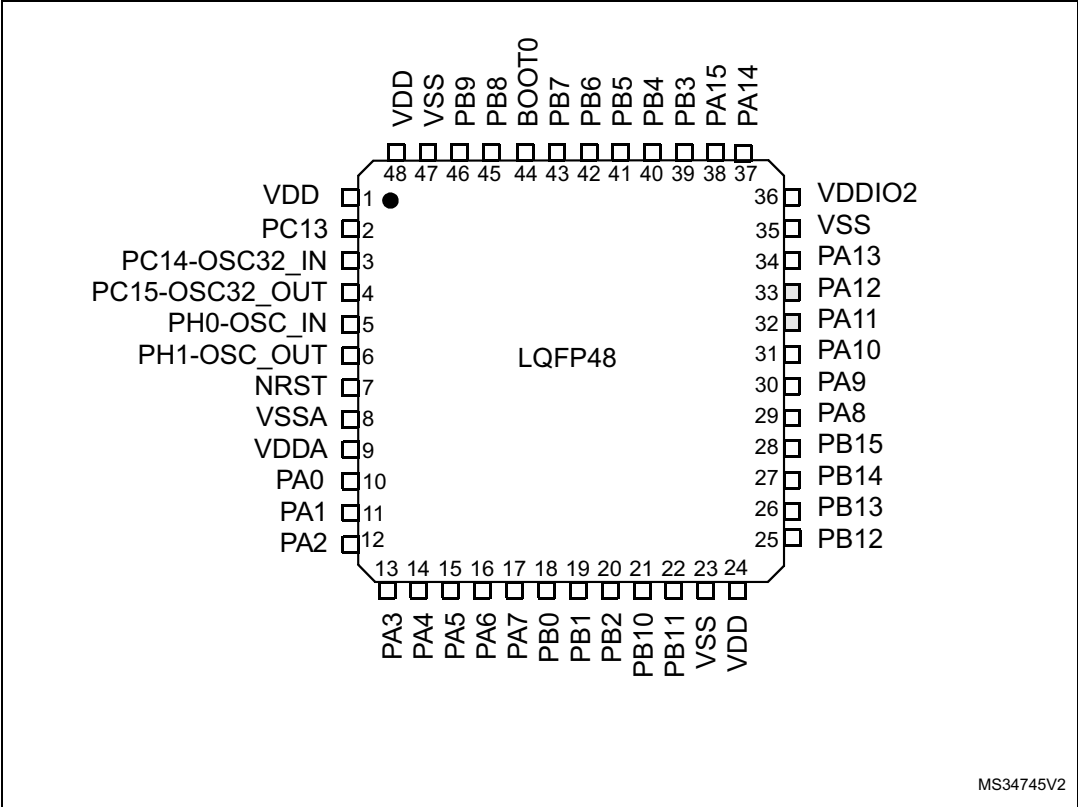
Several peripherals are directly interconnected. This allows autonomous communication between peripherals, thus saving CPU resources and power consumption. In addition, these hardware connections allow fast and predictable latency.

Depending on peripherals, these interconnections can operate in Run, Sleep, Low-power run, Low-power sleep and Stop modes.

Table 6. STM32L0xx peripherals interconnect matrix

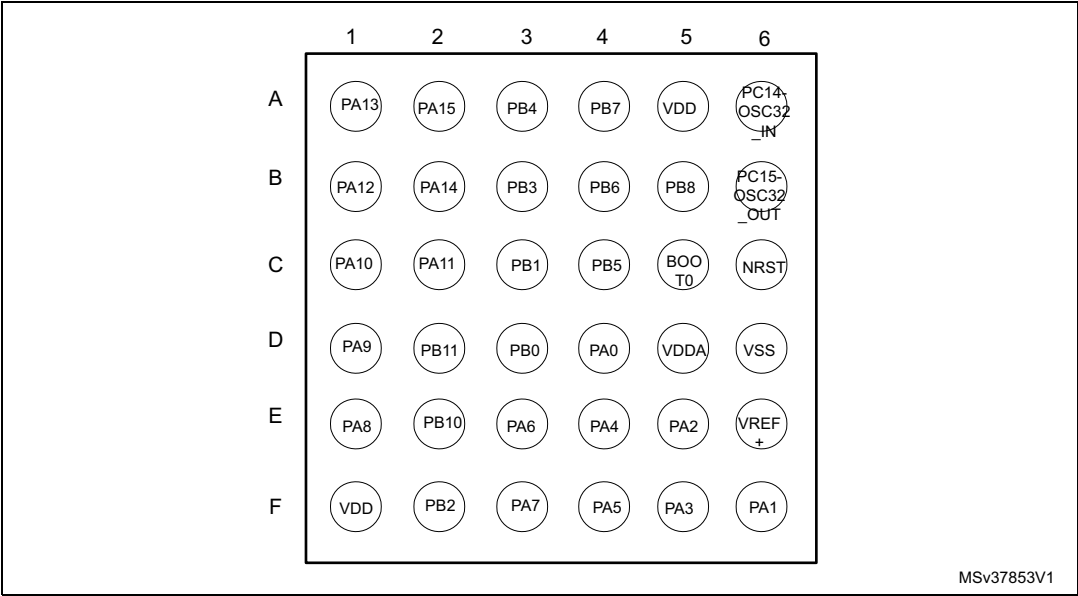
Interconnect source	Interconnect destination	Interconnect action	Run	Sleep	Low-power run	Low-power sleep	Stop
COMPx	TIM2, TIM21, TIM22	Timer input channel, trigger from analog signals comparison	Y	Y	Y	Y	-
	LPTIM	Timer input channel, trigger from analog signals comparison	Y	Y	Y	Y	Y
TIMx	TIMx	Timer triggered by other timer	Y	Y	Y	Y	-

Figure 5. STM32L051x6/8 LQFP48 pinout - 7 x 7 mm



1. The above figure shows the package top view.
2. I/O supplied by VDDIO2.

Figure 6. STM32L051x6/8 WLCSP36 ballout



1. The above figure shows the package top view.

Table 15. STM32L051x6/8 pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	TFBGA64	LQFP48	WLCSP36 ⁽¹⁾	LQFP32	UFQFPN32						
33	H8	25	-	-	-	PB12	I/O	FT	-	SPI2_NSS/I2S2_WS, LPUART1_RTS_DE, EVENTOUT	-
34	G8	26	-	-	-	PB13	I/O	FTf	-	SPI2_SCK/I2S2_CK, LPUART1_CTS, I2C2_SCL, TIM21_CH1	-
35	F8	27	-	-	-	PB14	I/O	FTf	-	SPI2_MISO/I 2S2_MCK, RTC_OUT, LPUART1_RTS_DE, I2C2_SDA, TIM21_CH2	-
36	F7	28	-	-	-	PB15	I/O	FT	-	SPI2_MOSI/I2S2_SD , RTC_REFIN	-
37	F6	-	-	-	-	PC6	I/O	FT	-	TIM22_CH1	-
38	E7	-	-	-	-	PC7	I/O	FT	-	TIM22_CH2	-
39	E8	-	-	-	-	PC8	I/O	FT	-	TIM22_ETR	-
40	D8	-	-	-	-	PC9	I/O	FT	-	TIM21_ETR	-
41	D7	29	E1	18	18	PA8	I/O	FT	-	MCO, EVENTOUT, USART1_CK	-
42	C7	30	D1	19	19	PA9	I/O	FT	-	MCO, USART1_TX	-
43	C6	31	C1	20	20	PA10	I/O	FT	-	USART1_RX	-
44	C8	32	C2	21	21	PA11	I/O	FT	-	SPI1_MISO, EVENTOUT, USART1_CTS, COMP1_OUT	-
45	B8	33	B1	22	22	PA12	I/O	FT	-	SPI1_MOSI, EVENTOUT, USART1_RTS_DE, COMP2_OUT	-
46	A8	34	A1	23	23	PA13	I/O	FT	-	SWDIO	-
47	D5	35	-	-	-	VSS	S		-	-	-

Table 15. STM32L051x6/8 pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	TFBGA64	LQFP48	WLCSP36 ⁽¹⁾	LQFP32	UFQFPN32						
48	E5	36	-	-	-	VDDIO2	S		-	-	-
49	A7	37	B2	24	24	PA14	I/O	FT	-	SWCLK, USART2_TX	
50	A6	38	A2	25	25	PA15	I/O	FT	-	SPI1_NSS, TIM2_ETR, EVENTOUT, USART2_RX, TIM2_CH1	-
51	B7	-	-	-	-	PC10	I/O	FT	-	LPUART1_TX	-
52	B6	-	-	-	-	PC11	I/O	FT	-	LPUART1_RX	-
53	C5	-	-	-	-	PC12	I/O	FT	-	-	-
54	B5	-	-	-	-	PD2	I/O	FT	-	LPUART1_RTS_DE	-
55	A5	39	B3	26	26	PB3	I/O	FT	-	SPI1_SCK, TIM2_CH2, EVENTOUT	COMP2_INN
56	A4	40	A3	27	27	PB4	I/O	FT	-	SPI1_MISO, EVENTOUT, TIM22_CH1	COMP2_INP
57	C4	41	C4	28	28	PB5	I/O	FT	-	SPI1_MOSI, LPTIM1_IN1, I2C1_SMBA, TIM22_CH2	COMP2_INP
58	D3	42	B4	29	29	PB6	I/O	FTf	-	USART1_TX, I2C1_SCL, LPTIM1_ETR	COMP2_INP
59	C3	43	A4	30	30	PB7	I/O	FTf	-	USART1_RX, I2C1_SDA, LPTIM1_IN2	COMP2_INP, PVD_IN
60	B4	44	C5	31	31	BOOT0	B		-	-	-
61	B3	45	B5	-	32	PB8	I/O	FTf	-	I2C1_SCL	-
62	A3	46	-	-	-	PB9	I/O	FTf	-	EVENTOUT, I2C1_SDA, SPI2_NSS/I2S2_WS	-

Table 15. STM32L051x6/8 pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	TFBGA64	LQFP48	WLCSP36 ⁽¹⁾	LQFP32	UFQFPN32						
63	D4	47	D6	32	-	VSS	S	-	-	-	-
64	E4	48	A5	1	1	VDD	S	-	-	-	-

1. PB9/12/13/14/15, PH0/1 and PC13 GPIOs should be configured as output and driven Low, even if they are not available on this package.

Table 18. Alternate function port C

Port		AF0	AF1	AF2
		LPUART1/LPTIM/TIM21/12/EVENTOUT	-	SPI2/I2S2/LPUART1/EVENTOUT
Port C	PC0	LPTIM1_IN1	-	EVENTOUT
	PC1	LPTIM1_OUT	-	EVENTOUT
	PC2	LPTIM1_IN2	-	SPI2_MISO/I2S2_MCK
	PC3	LPTIM1_ETR	-	SPI2_MOSI/I2S2_SD
	PC4	EVENTOUT	-	LPUART1_TX
	PC5		-	LPUART1_RX
	PC6	TIM22_CH1	-	-
	PC7	TIM22_CH2	-	-
	PC8	TIM22_ETR	-	-
	PC9	TIM21_ETR	-	-
	PC10	LPUART1_TX	-	-
	PC11	LPUART1_RX	-	-
	PC12	-	-	-
	PC13	-	-	-
	PC14	-	-	-
	PC15	-	-	-

Table 19. Alternate function port D

Port		AF0	AF1
		LPUART1	-
Port D	PD2	LPUART1_RTS_DE	-

6 Electrical characteristics

6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to V_{SS} .

6.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at $T_A = 25\text{ }^{\circ}\text{C}$ and $T_A = T_{A\text{max}}$ (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation ($\text{mean} \pm 3\sigma$).

6.1.2 Typical values

Unless otherwise specified, typical data are based on $T_A = 25\text{ }^{\circ}\text{C}$, $V_{DD} = 3.6\text{ V}$ (for the $1.65\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated ($\text{mean} \pm 2\sigma$).

6.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 10](#).

6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 11](#).

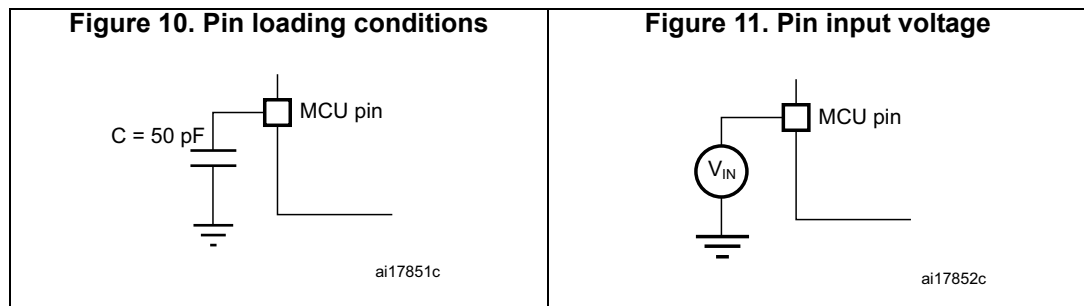


Table 27. Current consumption in Run mode, code with data processing running from Flash

Symbol	Parameter	Conditions		f _{HCLK}	Typ	Max ⁽¹⁾	Unit
I _{DD} (Run from Flash)	Supply current in Run mode, code executed from Flash	f _{HSE} = f _{HCLK} up to 16 MHz included, f _{HSE} = f _{HCLK} /2 above 16 MHz (PLL ON) ⁽²⁾	Range 3, V _{CORE} =1.2 V VOS[1:0]=11	1 MHz	165	230	μA
				2 MHz	290	360	
				4 MHz	555	630	
			Range 2, V _{CORE} =1.5 V, VOS[1:0]=10,	4 MHz	0.665	0.74	mA
				8 MHz	1.3	1.4	
				16 MHz	2.6	2.8	
			Range 1, V _{CORE} =1.8 V, VOS[1:0]=01	8 MHz	1.55	1.7	
				16 MHz	3.1	3.4	
				32 MHz	6.3	6.8	
		MSI clock	Range 3, V _{CORE} =1.2 V, VOS[1:0]=11	65 kHz	36.5	110	μA
				524 kHz	99.5	190	
				4.2 MHz	620	700	
		HSI clock	Range 2, V _{CORE} =1.5 V, VOS[1:0]=10,	16 MHz	2.6	2.9	mA
				32 MHz	6.25	7	

1. Guaranteed by characterization results at 125 °C, unless otherwise specified.

2. Oscillator bypassed (HSEBYP = 1 in RCC_CR register).

Table 28. Current consumption in Run mode vs code type, code with data processing running from Flash

Symbol	Parameter	Conditions			f _{HCLK}	Typ	Unit
I _{DD} (Run from Flash)	Supply current in Run mode, code executed from Flash	f _{HSE} = f _{HCLK} up to 16 MHz included, f _{HSE} = f _{HCLK} /2 above 16 MHz (PLL ON) ⁽¹⁾	Range 3, V _{CORE} =1.2 V, VOS[1:0]=11	Dhrystone	4 MHz	555	μA
				CoreMark		585	
				Fibonacci		440	
				while(1)		355	
				while(1), prefetch OFF		353	
			Range 1, V _{CORE} =1.8 V, VOS[1:0]=01	Dhrystone	32 MHz	6.3	mA
				CoreMark		6.3	
				Fibonacci		6.55	
				while(1)		5.4	
				while(1), prefetch OFF		5.2	

1. Oscillator bypassed (HSEBYP = 1 in RCC_CR register).

Table 29. Current consumption in Run mode, code with data processing running from RAM

Symbol	Parameter	Conditions		f _{HCLK}	Typ	Max ⁽¹⁾	Unit
I _{DD} (Run from RAM)	Supply current in Run mode, code executed from RAM, Flash switched off	f _{HSE} = f _{HCLK} up to 16 MHz included, f _{HSE} = f _{HCLK} /2 above 16 MHz (PLL ON) ⁽²⁾	Range 3, V _{CORE} =1.2 V, VOS[1:0]=11	1 MHz	135	170	μA
				2 MHz	240	270	
				4 MHz	450	480	
			Range 2, V _{CORE} =1.5 V, VOS[1:0]=10	4 MHz	0.52	0.6	mA
				8 MHz	1	1.2	
				16 MHz	2	2.3	
			Range 1, V _{CORE} =1.8 V, VOS[1:0]=01	8 MHz	1.25	1.4	
				16 MHz	2.45	2.8	
				32 MHz	5.1	5.4	
		MSI clock	Range 3, V _{CORE} =1.2 V, VOS[1:0]=11	65 kHz	34.5	75	μA
				524 kHz	83	120	
				4.2 MHz	485	540	
		HSI16 clock source (16 MHz)	Range 2, V _{CORE} =1.5 V, VOS[1:0]=10	16 MHz	2.1	2.3	mA
			Range 1, V _{CORE} =1.8 V, VOS[1:0]=01	32 MHz	5.1	5.6	

1. Guaranteed by characterization results at 125 °C, unless otherwise specified.

2. Oscillator bypassed (HSEBYP = 1 in RCC_CR register).

Table 30. Current consumption in Run mode vs code type, code with data processing running from RAM⁽¹⁾

Symbol	Parameter	Conditions			f _{HCLK}	Typ	Unit
I _{DD} (Run from RAM)	Supply current in Run mode, code executed from RAM, Flash switched off	f _{HSE} = f _{HCLK} up to 16 MHz included, f _{HSE} = f _{HCLK} /2 above 16 MHz (PLL ON) ⁽²⁾	Range 3, V _{CORE} =1.2 V, VOS[1:0]=11	Dhrystone	4 MHz	450	μA
				CoreMark		575	
				Fibonacci		370	
				while(1)		340	
		Range 1, V _{CORE} =1.8 V, VOS[1:0]=01		Dhrystone	32 MHz	5.1	mA
				CoreMark		6.25	
				Fibonacci		4.4	
				while(1)		4.7	

1. Guaranteed by characterization results, unless otherwise specified.

2. Oscillator bypassed (HSEBYP = 1 in RCC_CR register).

Table 46. MSI oscillator characteristics (continued)

Symbol	Parameter	Condition	Typ	Max	Unit
$I_{DD(MSI)}^{(2)}$	MSI oscillator power consumption	MSI range 0	0.75	-	μA
		MSI range 1	1	-	
		MSI range 2	1.5	-	
		MSI range 3	2.5	-	
		MSI range 4	4.5	-	
		MSI range 5	8	-	
		MSI range 6	15	-	
$t_{SU(MSI)}$	MSI oscillator startup time	MSI range 0	30	-	μs
		MSI range 1	20	-	
		MSI range 2	15	-	
		MSI range 3	10	-	
		MSI range 4	6	-	
		MSI range 5	5	-	
		MSI range 6, Voltage range 1 and 2	3.5	-	
		MSI range 6, Voltage range 3	5	-	
$t_{STAB(MSI)}^{(2)}$	MSI oscillator stabilization time	MSI range 0	-	40	μs
		MSI range 1	-	20	
		MSI range 2	-	10	
		MSI range 3	-	4	
		MSI range 4	-	2.5	
		MSI range 5	-	2	
		MSI range 6, Voltage range 1 and 2	-	2	
		MSI range 3, Voltage range 3	-	3	
$f_{OVER(MSI)}$	MSI oscillator frequency overshoot	Any range to range 5	-	4	MHz
		Any range to range 6	-	6	

1. This is a deviation for an individual part, once the initial frequency has been measured.

2. Guaranteed by characterization results.

Output voltage levels

Unless otherwise specified, the parameters given in [Table 57](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 23](#). All I/Os are CMOS and TTL compliant.

Table 57. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	CMOS port ⁽²⁾ , $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	TTL port ⁽²⁾ , $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	TTL port ⁽²⁾ , $I_{IO} = -6 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	2.4	-	
$V_{OL}^{(1)(4)}$	Output low level voltage for an I/O pin	$I_{IO} = +15 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	1.3	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	$I_{IO} = -15 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-1.3$	-	
$V_{OL}^{(1)(4)}$	Output low level voltage for an I/O pin	$I_{IO} = +4 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} < 3.6 \text{ V}$	-	0.45	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	$I_{IO} = -4 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-0.45$	-	
$V_{OLFM+}^{(1)(4)}$	Output low level voltage for an FTf I/O pin in Fm+ mode	$I_{IO} = 20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
		$I_{IO} = 10 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in [Table 21](#). The sum of the currents sunk by all the I/Os (I/O ports and control pins) must always be respected and must not exceed $\Sigma I_{IO(PIN)}$.
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in [Table 21](#). The sum of the currents sourced by all the I/Os (I/O ports and control pins) must always be respected and must not exceed $\Sigma I_{IO(PIN)}$.
4. Guaranteed by characterization results.

Table 71. SPI characteristics in voltage Range 2 ⁽¹⁾

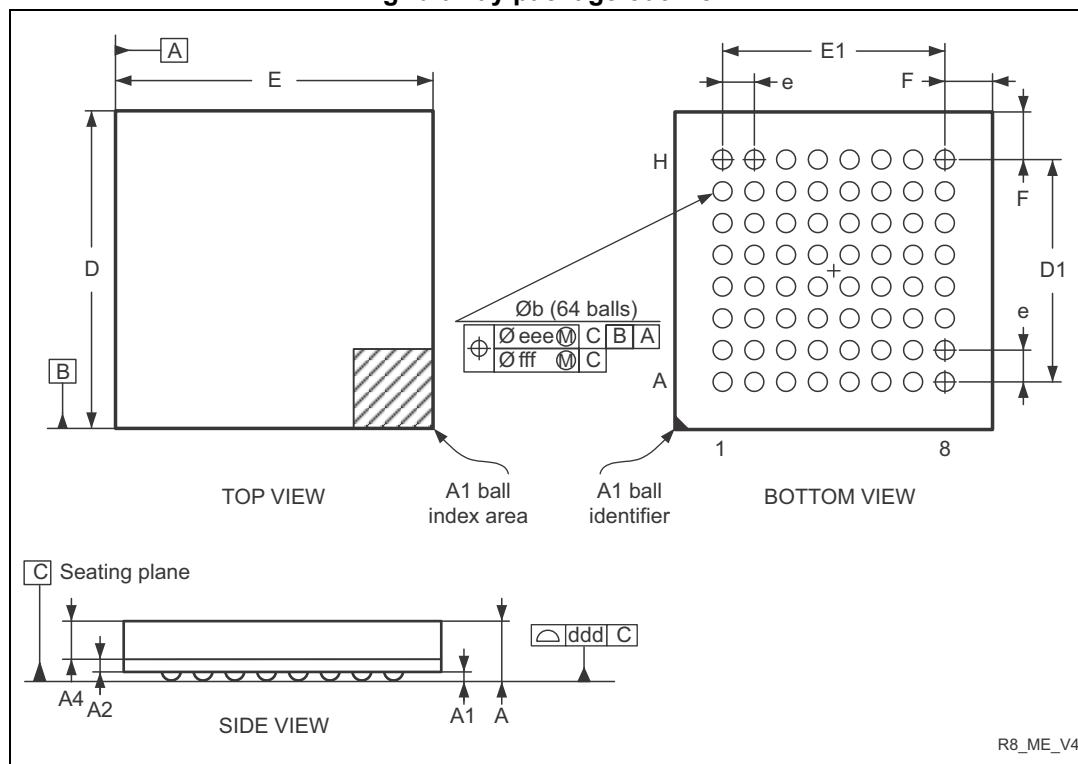
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master mode	-	-	8	MHz
		Slave mode Transmitter $1.65 < V_{DD} < 3.6V$			8	
		Slave mode Transmitter $2.7 < V_{DD} < 3.6V$			8 ⁽²⁾	
$Duty_{(SCK)}$	Duty cycle of SPI clock frequency	Slave mode	30	50	70	%
$t_{su(NSS)}$	NSS setup time	Slave mode, SPI presc = 2	$4 \cdot T_{pclk}$	-	-	ns
$t_{h(NSS)}$	NSS hold time	Slave mode, SPI presc = 2	$2 \cdot T_{pclk}$	-	-	
$t_{w(SCKH)}$ $t_{w(SCKL)}$	SCK high and low time	Master mode	$T_{pclk} - 2$	T_{pclk}	$T_{pclk} + 2$	
$t_{su(MI)}$	Data input setup time	Master mode	0	-	-	
$t_{su(SI)}$		Slave mode	3	-	-	
$t_{h(MI)}$	Data input hold time	Master mode	11	-	-	
$t_{h(SI)}$		Slave mode	4.5	-	-	
$t_{a(SO)}$	Data output access time	Slave mode	18	-	52	
$t_{dis(SO)}$	Data output disable time	Slave mode	12	-	42	
$t_{v(SO)}$	Data output valid time	Slave mode	-	20	56.5	
$t_{v(MO)}$		Master mode	-	5	9	
$t_{h(SO)}$	Data output hold time	Slave mode	13	-	-	
$t_{h(MO)}$		Master mode	3	-	-	

1. Guaranteed by characterization results.

2. The maximum SPI clock frequency in slave transmitter mode is determined by the sum of $t_{v(SO)}$ and $t_{su(MI)}$ which has to fit into SCK low or high phase preceding the SCK sampling edge. This value can be achieved when the SPI communicates with a master having $t_{su(MI)} = 0$ while $Duty_{(SCK)} = 50\%$.

7.2 TFBGA64 package information

Figure 40. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch thin profile fine pitch ball grid array package outline



1. Drawing is not to scale.

Table 75. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ball grid array package mechanical data

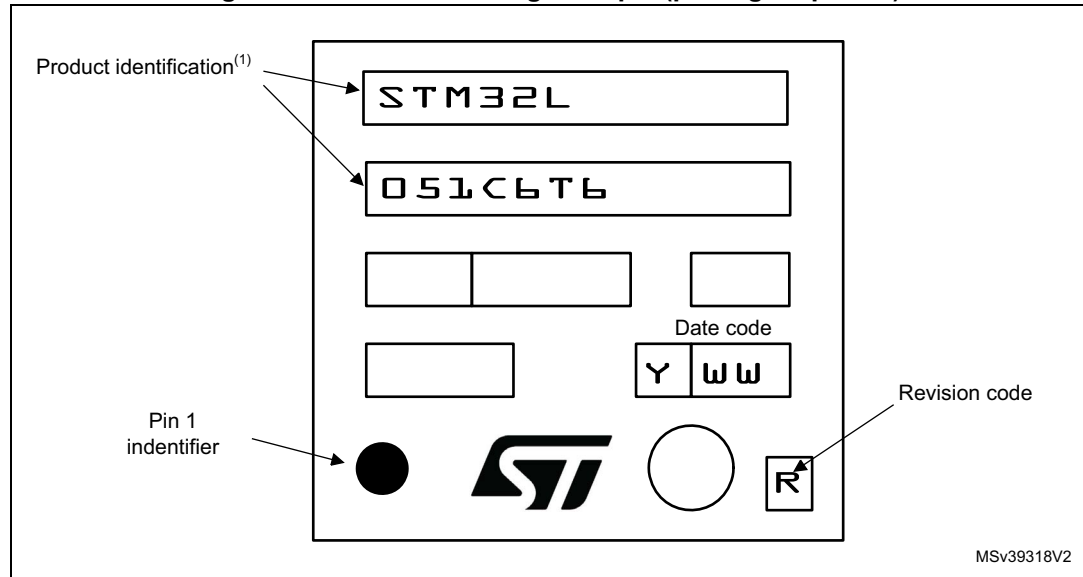
Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.200	-	-	0.0472
A1	0.150	-	-	0.0059	-	-
A2	-	0.200	-	-	0.0079	-
A4	-	-	0.600	-	-	0.0236
b	0.250	0.300	0.350	0.0098	0.0118	0.0138
D	4.850	5.000	5.150	0.1909	0.1969	0.2028
D1	-	3.500	-	-	0.1378	-
E	4.850	5.000	5.150	0.1909	0.1969	0.2028
E1	-	3.500	-	-	0.1378	-
e	-	0.500	-	-	0.0197	-
F	-	0.750	-	-	0.0295	-

Device marking for LQFP48

The following figure gives an example of topside marking versus pin 1 position identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

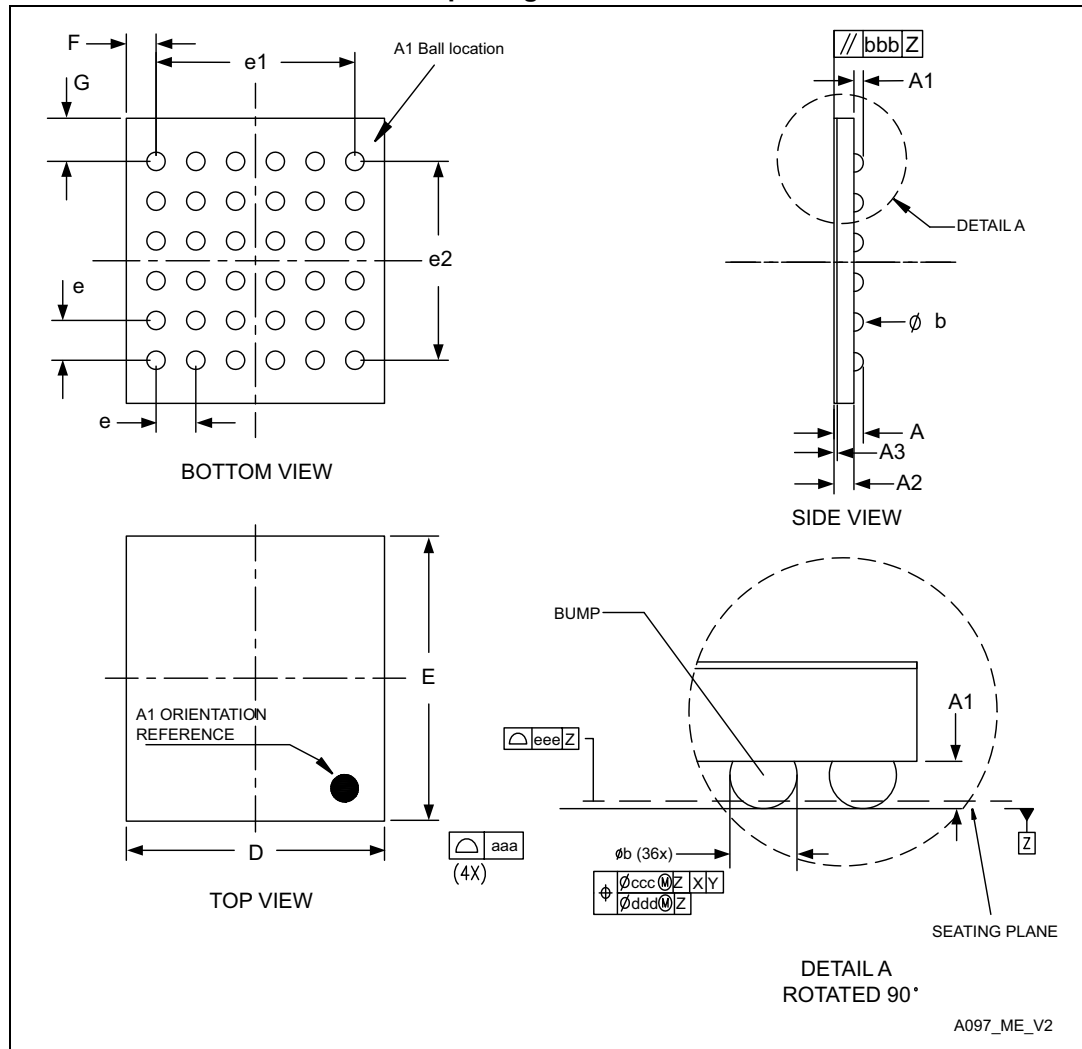
Figure 45. LQFP48 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

7.5 Thin WLCSP36 package information

Figure 49. Thin WLCSP36 - 2.61 x 2.88 mm, 0.4 mm pitch wafer level chip scale package outline

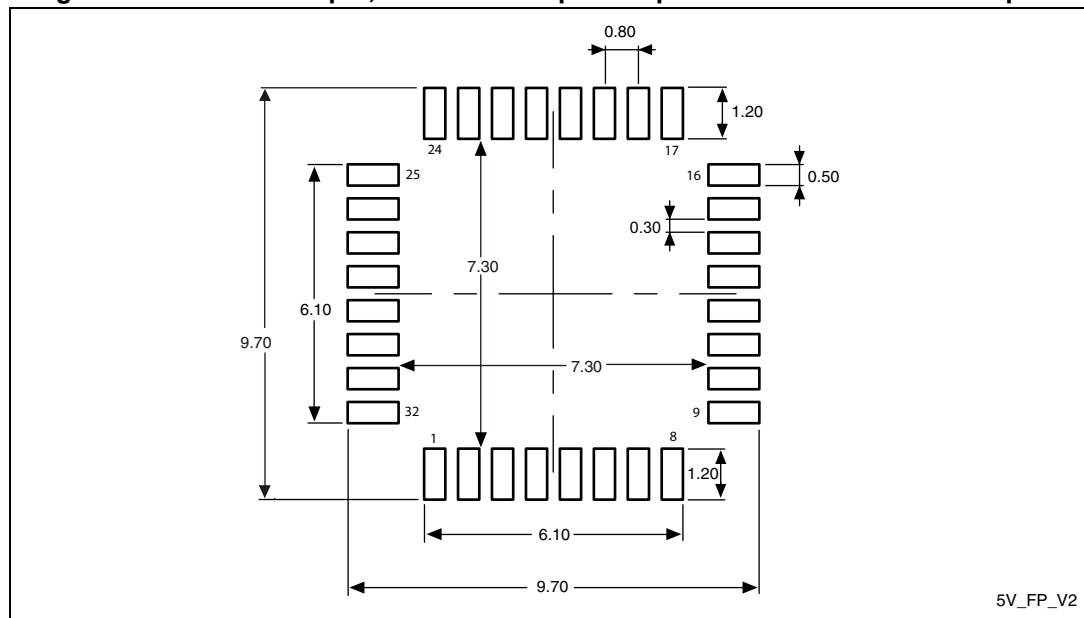


1. Drawing is not to scale.
2. b dimensions is measured at the maximum bump diameter parallel to primary datum Z.
3. Primary datum Z and seating plane are defined by the spherical crowns of the bump.
4. Bump position designation per JESD 95-1, SPP-010.

Table 82. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data

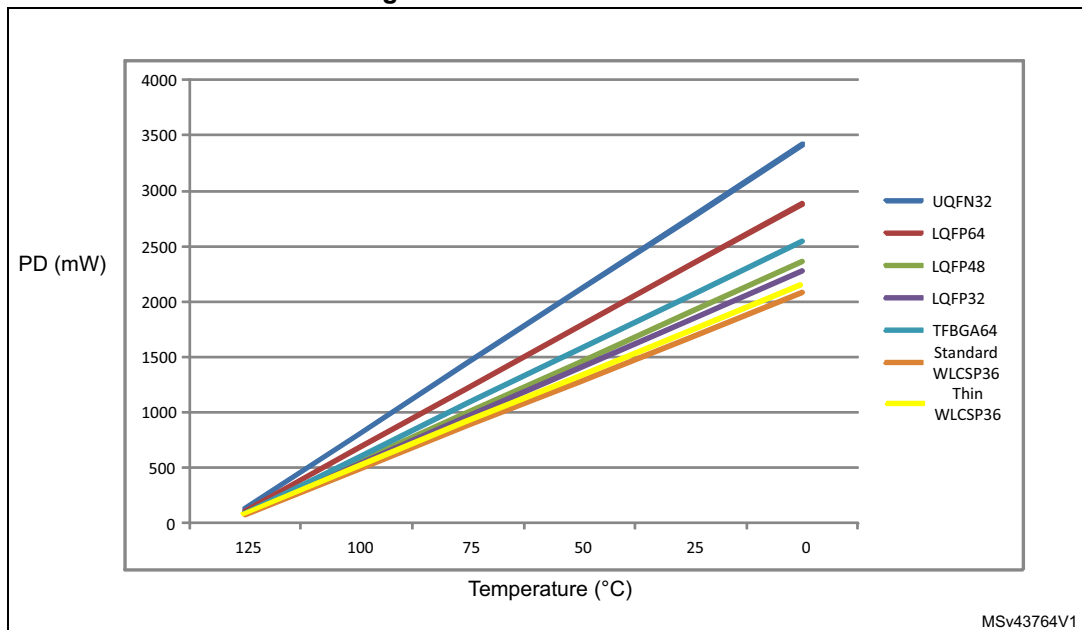
Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.600	-	-	0.2205	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.600	-	-	0.2205	-
e	-	0.800	-	-	0.0315	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 52. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat recommended footprint

1. Dimensions are expressed in millimeters.

Figure 57. Thermal resistance



7.8.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org.